

JAN 18 2001

FORM PTO-1419 U.S. DEPARTMENT OF COMMERCE PATENT & TRADEMARK OFFICE		ATTY DOCKET NO.: 18940/36899	SERIAL NO.: 09/703,845
<b>LIST OF DOCUMENTS CITED BY APPLICANT</b> (Use several sheets if necessary)			
APPLICANT M. Toshiyuki, Y. Masami, H. Yoshihiro			
FILING DATE November 2, 2000			GROUP 2858

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
IT	AA	3,753,373	8/21/1973	Brown			
JA	AB	4,473,796	9/25/1984	Nankivil			
JA	AC	4,498,044	2/5/1985	Horn			
JA	AD	5,416,470	5/18/1995	Tanaka et al.			
JA	AE	5,701,101	12/23/1997	Weinhardt et al.			
JA	AF	5,808,516	9/15/1998	Barber			
JA	AG	5,886,529	3/23/1999	Wakamatsu			
JA	AH	5,986,456	11/16/1999	Yamashita			
JA	AI	6,054,867	4/25/2000	Wakamatsu			
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							Yes	No
JA	AL	3413849 A1	8/22/1985	Germany				
JA	AM	61-14578	1/22/1986	Japan				
JA	AN	06180336	6/28/1994	Japan (Abstract)				
JA	AO	4135991 C1	12/17/1992	Germany				
JA	AP	9-280806	10/31/1997	Japan				

## OTHER PRIOR ART (Including Author, Title, Date Pertinent Pages, Etc.)

JA	AQ		An On-Chip, Attofarad Interconnect Charge-Based Capacitance Measurement (CBCM Technique), J.C. Chen, B.W. McGaughy, D. Sylvester, C. Hu, Department of EECS, University of California Berkeley, 1996
JA	AR		On-Chip Measurement of Interconnect Capacitances in a CMOS Process, A. Khalkhal and P. Nouet, Laboratoire d'Informatique, de Robotique et de Microelectronique de Montpellier (LIRMM), Proc. IEEE 1995 Int. Conference on Microelectronic Test Structures, Vol. 8, March, 1995
JA	AS		Efficient extraction of metal parasitic capacitances, G.J. Gaston and I.G. Daniels, GEC Plessey Semiconductors Ltd., Proc. IEEE 1995 Int. Conference on Microelectronic Test Structures, Vol. 8, March, 1995